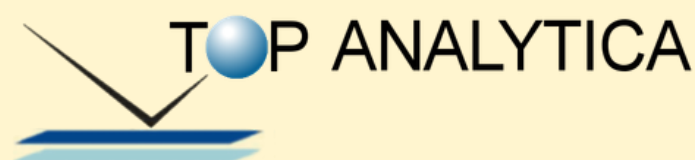


Advanced Sample Preparation Workshop & BIB User Meeting

18.—19.11.2026

Top Analytica, Ruukinkatu 4, Turku, Finland



Participation Fees

Day 1 Workshop €50 + VAT
Includes catering & evening social event

Day 2 User Meeting FREE!

Wednesday 18.11.2026 — Advanced Sample Prep Workshop

Advanced Broad Ion Beam Technology

Insights from Justyna Grzonka,
Senior Application Specialist at
Hitachi High-Tech Europe GmbH

See Your Own Samples in Action

Live demo results and SEM comparative analysis.

Real-World Success Stories

Inspiring case studies by Top Analytica.

Behind the Scenes

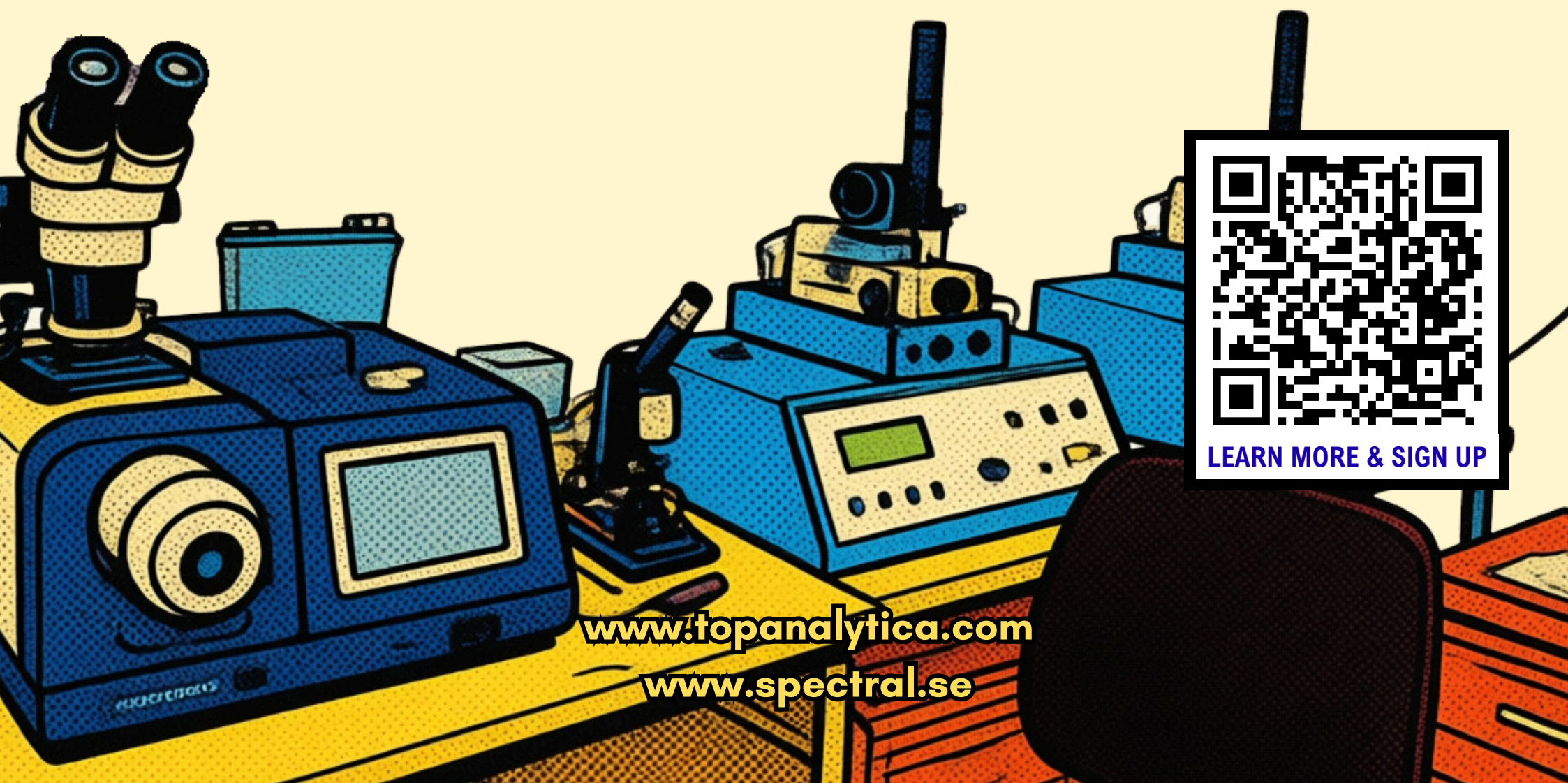
Exclusive laboratory walkthrough and facility tour.

Connect & Unwind

Wrap up the day with a relaxed dinner and networking.

Visit our website for updates and full details!

Deadlines Submit Demo Samples by **Sept 15** | Register by **Nov 6**



www.topanalytica.com

www.spectral.se

Advanced Sample Preparation Workshop & BIB User Meeting



TOP ANALYTICA

Spectral

18.—19.11.2026

Top Analytica, Ruukinkatu 4, Turku, Finland

Thursday 19.11.2026 — BIB User Meeting: Theory into practice

Peer-to-Peer Insights

Doing something cool with ion milling?
Present your work! Share your
Broad Ion Beam case study, trade tips, and
spark open discussion with fellow users.

Hands-on Instrument Session

Live demonstrations of sample preparation,
workflow optimization, automation, and
camera solutions.

Optimize Your Workflow

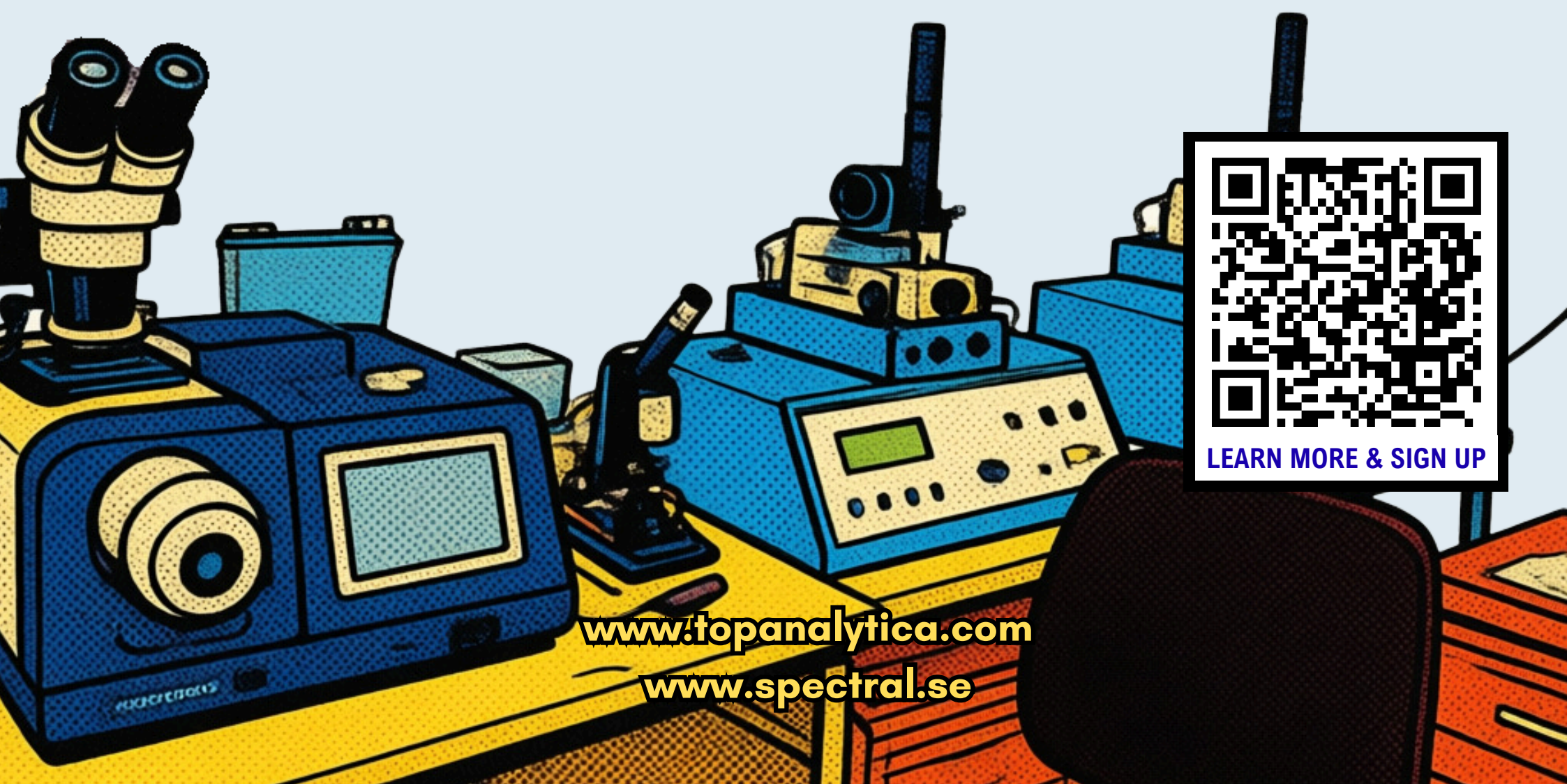
Practical tips to elevate your daily
microscopy work.

Strengthen Your Network

Connect with the local microscopy
community.

Visit our website for updates and full details!

Deadlines Submit Demo Samples by **Sept 15** | Register by **Nov 6**



LEARN MORE & SIGN UP

www.topanalytica.com

www.spectral.se